

OptiMOS[®]-T2 Power-Transistor

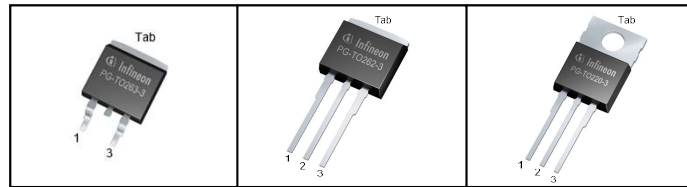
Product Summary

| | | |
|--------------------------------|-----|------------|
| V_{DS} | 80 | V |
| $R_{DS(on),max}$ (SMD version) | 4.1 | m Ω |
| I_D | 120 | A |

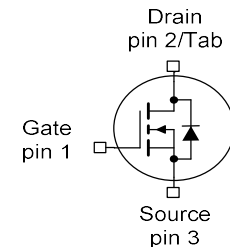
Features

- N-channel - Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- RoHS compliant
- 100% Avalanche tested

PG-TO263-3-2 PG-TO262-3-1 PG-TO220-3-1



| Type | Package | Marking |
|----------------|--------------|---------|
| IPB120N08S4-04 | PG-TO263-3-2 | 4N0804 |
| IPI120N08S4-04 | PG-TO262-3-1 | 4N0804 |
| IPP120N08S4-04 | PG-TO220-3-1 | 4N0804 |


Maximum ratings, at $T_j=25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|---|----------------|---|--------------|------------------|
| Continuous drain current | I_D | $T_C=25^\circ\text{C}$, $V_{GS}=10\text{V}^{(1)}$ | 120 | A |
| | | $T_C=100^\circ\text{C}$, $V_{GS}=10\text{V}^{(2)}$ | 108 | |
| Pulsed drain current ⁽²⁾ | $I_{D,pulse}$ | $T_C=25^\circ\text{C}$ | 480 | |
| Avalanche energy, single pulse ⁽²⁾ | E_{AS} | $I_D=60\text{A}$ | 310 | mJ |
| Avalanche current, single pulse | I_{AS} | - | 99 | A |
| Gate source voltage | V_{GS} | - | ± 20 | V |
| Power dissipation | P_{tot} | $T_C=25^\circ\text{C}$ | 179 | W |
| Operating and storage temperature | T_j, T_{stg} | - | -55 ... +175 | $^\circ\text{C}$ |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Thermal characteristics²⁾

| | | | | | | |
|--|------------|--|---|---|------|-----|
| Thermal resistance, junction - case | R_{thJC} | - | - | - | 0.84 | K/W |
| Thermal resistance, junction - ambient, leaded | R_{thJA} | - | - | - | 62 | |
| SMD version, device on PCB | R_{thJA} | minimal footprint | - | - | 62 | |
| | | 6 cm ² cooling area ³⁾ | - | - | 40 | |

Electrical characteristics, at $T_j=25$ °C, unless otherwise specified
Static characteristics

| | | | | | | |
|----------------------------------|---------------|---|-----|------|-----|------------|
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $V_{GS}=0V, I_D=1mA$ | 80 | - | - | V |
| Gate threshold voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=120\mu A$ | 2.0 | 3.0 | 4.0 | |
| Zero gate voltage drain current | I_{DSS} | $V_{DS}=80V, V_{GS}=0V$ | - | 0.03 | 1 | μA |
| | | $V_{DS}=80V, V_{GS}=0V, T_j=125^\circ C^{2)}$ | - | 10 | 200 | |
| Gate-source leakage current | I_{GSS} | $V_{GS}=20V, V_{DS}=0V$ | - | - | 100 | nA |
| Drain-source on-state resistance | $R_{DS(on)}$ | $V_{GS}=10V, I_D=100A$ | - | 3.8 | 4.4 | m Ω |
| | | $V_{GS}=10V, I_D=100A, SMD$ version | - | 3.5 | 4.1 | |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Dynamic characteristics²⁾

| | | | | | | |
|------------------------------|--------------|--|---|------|------|----|
| Input capacitance | C_{iss} | $V_{GS}=0V, V_{DS}=25V,$ $f=1MHz$ | - | 4850 | 6450 | pF |
| Output capacitance | C_{oss} | | - | 1870 | 2490 | |
| Reverse transfer capacitance | C_{rss} | | - | 100 | 200 | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=40V, V_{GS}=10V,$ $I_D=120A, R_G=3.5\Omega$ | - | 20 | - | ns |
| Rise time | t_r | | - | 10 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 30 | - | |
| Fall time | t_f | | - | 35 | - | |

Gate Charge Characteristics²⁾

| | | | | | | |
|-----------------------|---------------|---|---|-----|----|----|
| Gate to source charge | Q_{gs} | $V_{DD}=60V, I_D=120A,$ $V_{GS}=0 \text{ to } 10V$ | - | 25 | 33 | nC |
| Gate to drain charge | Q_{gd} | | - | 15 | 30 | |
| Gate charge total | Q_g | | - | 70 | 95 | |
| Gate plateau voltage | $V_{plateau}$ | | - | 5.2 | - | V |

Reverse Diode

| | | | | | | |
|--|---------------|---|---|-----|-----|----|
| Diode continuous forward current ²⁾ | I_S | $T_C=25^\circ C$ | - | - | 120 | A |
| Diode pulse current ²⁾ | $I_{S,pulse}$ | | - | - | 480 | |
| Diode forward voltage | V_{SD} | $V_{GS}=0V, I_F=100A,$ $T_j=25^\circ C$ | - | 0.9 | 1.3 | V |
| Reverse recovery time ²⁾ | t_{rr} | $V_R=40V, I_F=50A,$ $di_F/dt=100A/\mu s$ | - | 70 | - | ns |
| Reverse recovery charge ²⁾ | Q_{rr} | | - | 130 | - | nC |

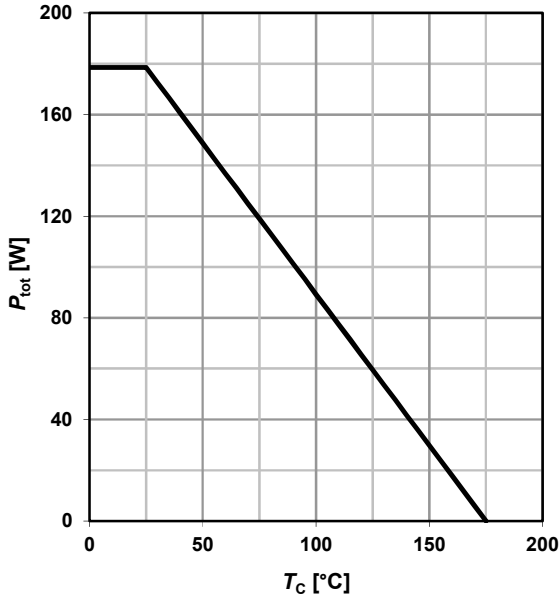
¹⁾ Current is limited by bondwire; with an $R_{thJC} = 0.84K/W$ the chip is able to carry 149A at 25°C.

²⁾ Specified by design. Not subject to production test.

³⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

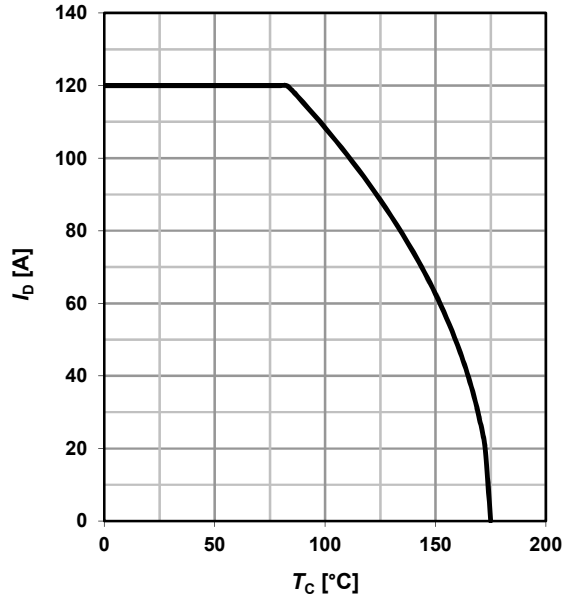
1 Power dissipation

$P_{tot} = f(T_C); V_{GS} \geq 6 \text{ V}$



2 Drain current

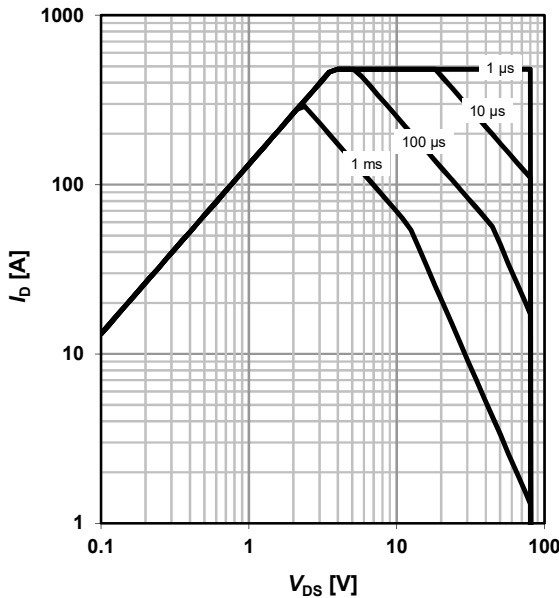
$I_D = f(T_C); V_{GS} = 10 \text{ V}; \text{SMD}$



3 Safe operating area

$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0; \text{SMD}$

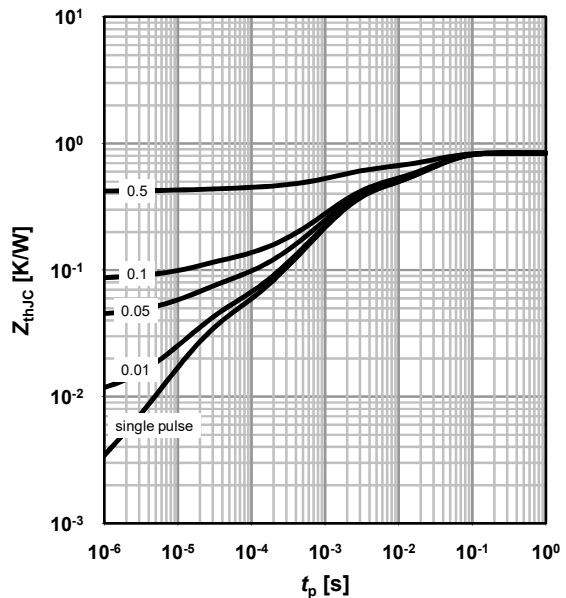
parameter: t_p



4 Max. transient thermal impedance

$Z_{thJC} = f(t_p)$

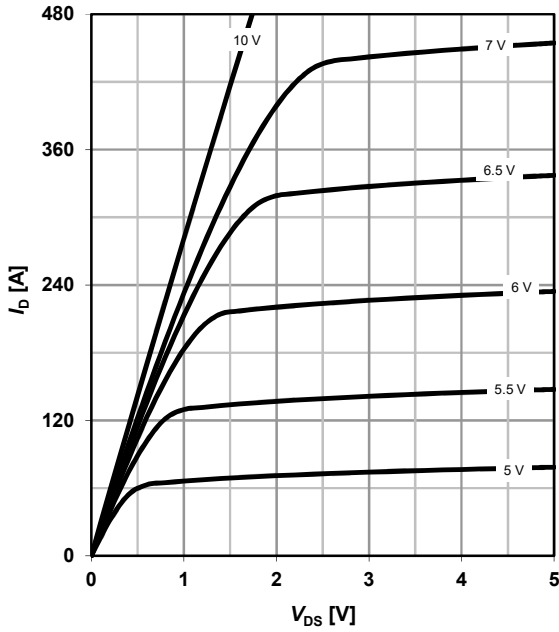
parameter: $D = t_p/T$



5 Typ. output characteristics

$I_D = f(V_{DS}); T_j = 25\text{ °C}; \text{SMD}$

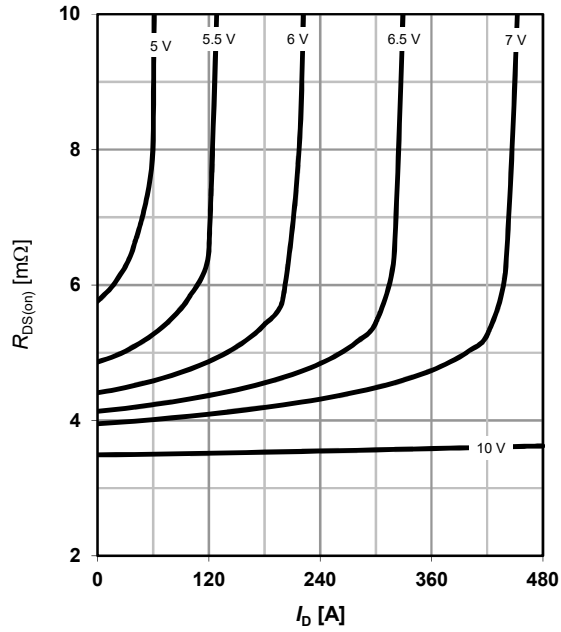
parameter: V_{GS}



6 Typ. drain-source on-state resistance

$R_{DS(on)} = f(I_D); T_j = 25\text{ °C}; \text{SMD}$

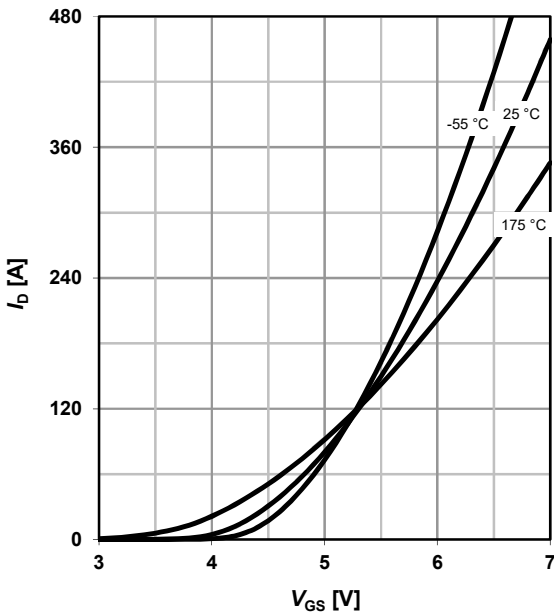
parameter: V_{GS}



7 Typ. transfer characteristics

$I_D = f(V_{GS}); V_{DS} = 6\text{ V}$

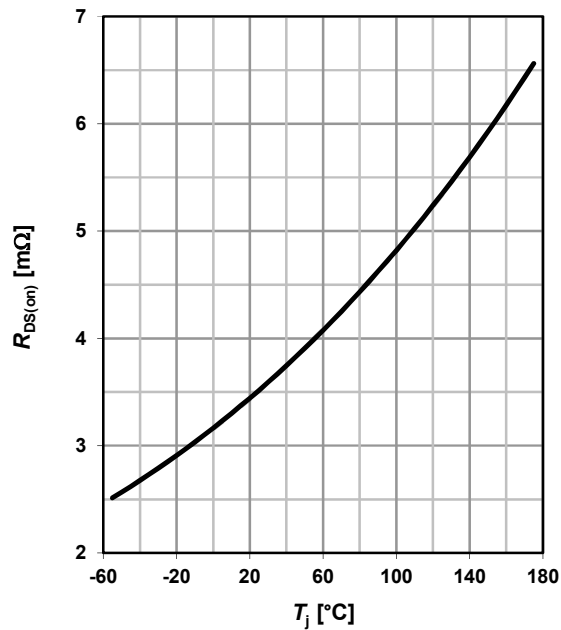
parameter: T_j



8 Typ. drain-source on-state resistance

$R_{DS(on)} = f(T_j); I_D = 120\text{ A}; V_{GS} = 10\text{ V}; \text{SMD}$

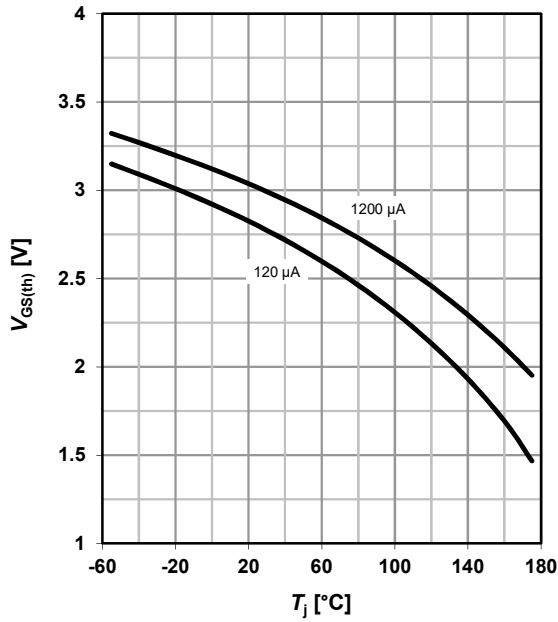
$\alpha = 0.4$



9 Typ. gate threshold voltage

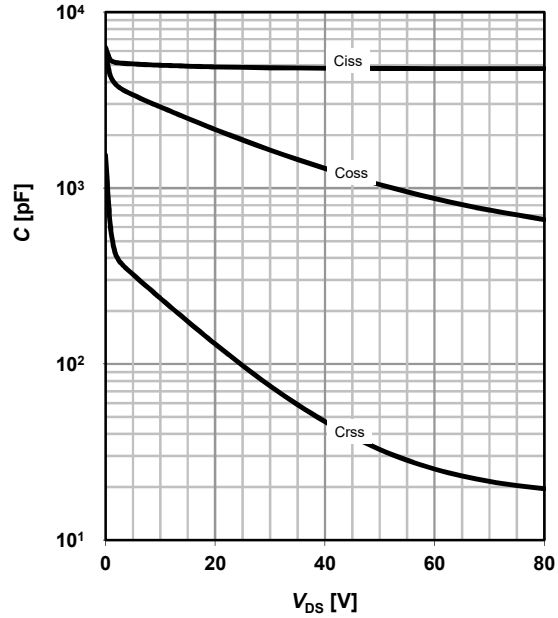
$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D



10 Typ. capacitances

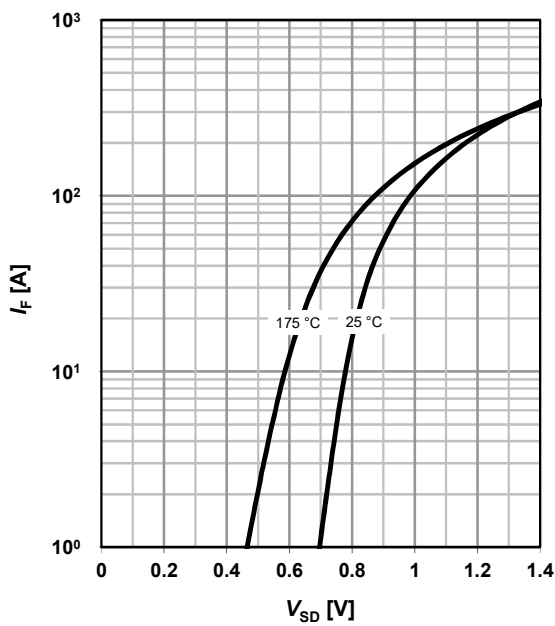
$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$



11 Typical forward diode characteristics

$I_F = f(V_{SD})$

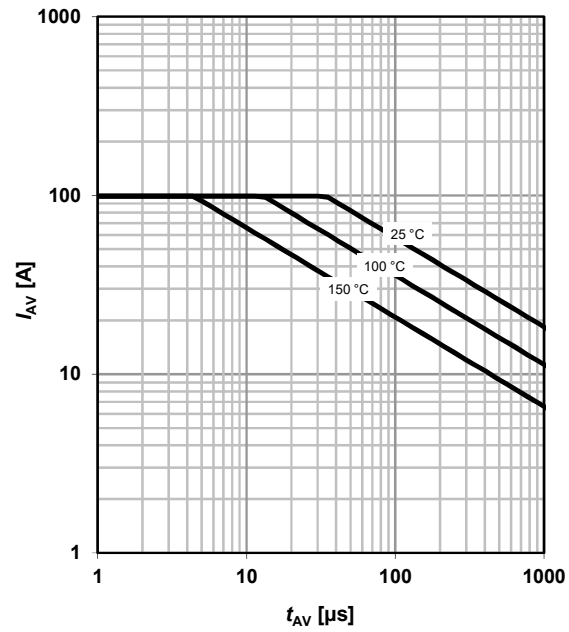
parameter: T_j



12 Avalanche characteristics

$I_{AS} = f(t_{AV})$

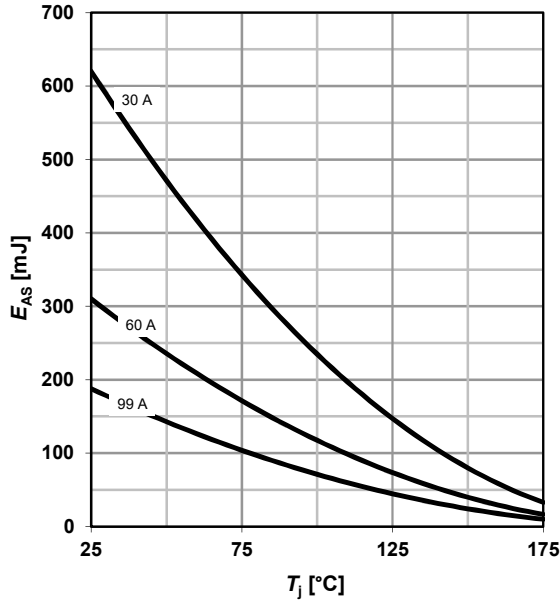
parameter: $T_{j(start)}$



13 Avalanche energy

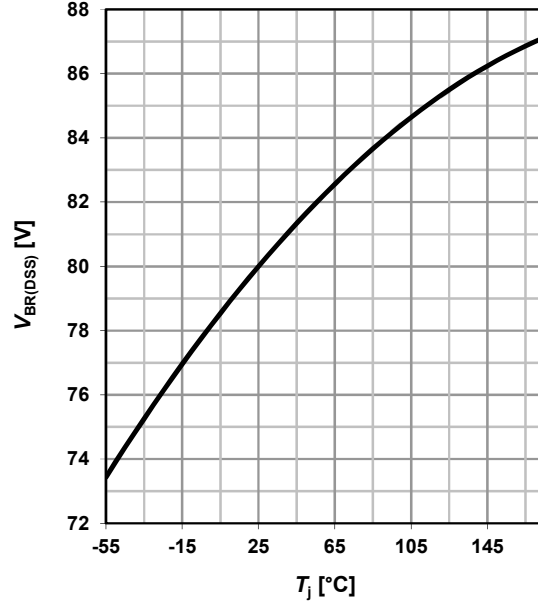
$E_{AS} = f(T_j)$

parameter: I_D



14 Drain-source breakdown voltage

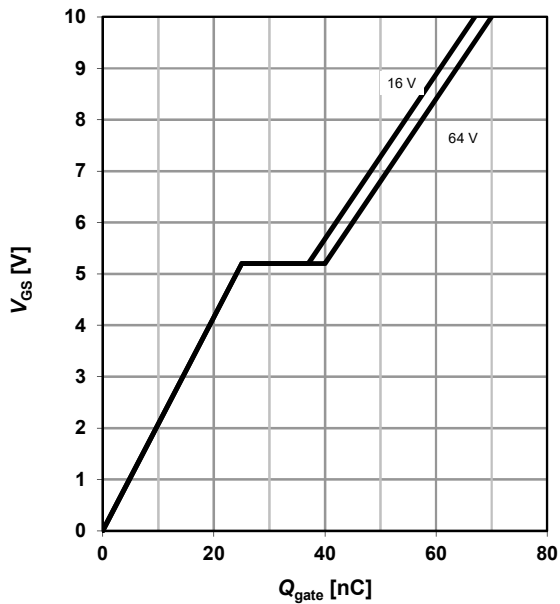
$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$



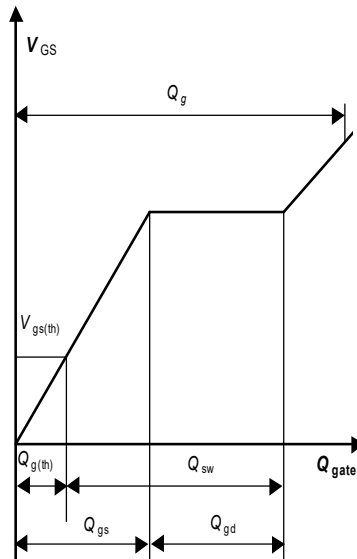
15 Typ. gate charge

$V_{GS} = f(Q_{gate}); I_D = 120 \text{ A pulsed}$

parameter: V_{DD}



16 Gate charge waveforms



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Revision History

| Version | Date | Changes |
|--------------|------------|--|
| Revision 1.0 | 2014-06-20 | Final data sheet |
| Revision 1.1 | 2022-08-24 | Diagram 8 Typ. drain-source on-state resistance: used α value clarified |